

## Search Results

BROWSE

SEARCH

IEEE XPLORE GUIDE

SUPPORT

Results for "((register)-in-metadata) &lt;and&gt; ((class)-in-metadata) &lt;and&gt; ((manager)&amp;..."

Your search matched 1 of 1860732 documents.



A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

New [Beta]  
Application  
Notes  
POWERED BY  
GLOBALSPEC

## Search Options

[View Session History](#)[New Search](#)

## Key

IEEE JNL	IEEE Journal or Magazine
IET JNL	IET Journal or Magazine
IEEE CNF	IEEE Conference Proceeding
IET CNF	IET Conference Proceeding
IEEE STD	IEEE Standard

Modify Search

(((register)-in-metadata) &lt;and&gt; ((class)-in-metadata) &lt;and&gt; ((manager)-in-metadata)

Search &gt;

☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

IEEE/ET

Books

Educational Courses

Application Notes [Beta]

IEEE/ET journals, transactions, letters, magazines, conference proceedings, and standards.

[view selected items](#) | [Select All](#) [Deselect All](#)

- ☐ 1. Metrics and tool for system assessment  
 Buccì, G.; Fioravanti, F.; Nesi, P.; Perlini, S.;  
[Engineering of Complex Computer Systems, 1998. ICECCS '98. Proceedings. Fourth IEEE International Conference on](#)  
 10-14 Aug. 1998 Page(s):36 - 46  
 Digital Object Identifier 10.1109/ICECCS.1998.706654  
[AbstractPlus](#) | Full Text: [PDF\(132 KB\)](#) IEEE CNF  
[Rights and Permissions](#)